

In the United States Patent and Trademark Office

Appn. Number: \_\_\_\_\_

Appn. Filed: \_\_\_\_\_

Applicant(s): Liphardt et al

Appn. Title: Sample Markings TO Reduce Backside Reflections

Examiner/GAU: \_\_\_\_\_ 1324

Mailed: With Application

At: \_\_\_\_\_

Information Disclosure Statement

Commissioner of Patents and Trademarks  
Washington, District of Columbia 20231

Sir:

Attached is a completed Form PTO-1449 and copies of the pertinent parts of the references cited thereon.

Following are comments on these references pursuant to Rule 98:

Patent Application No. 2002/0113200 A1 was identified as an aperture 103A is disclosed which can be placed near a detector to block entry of one of two beams from different sources.

Patent No. 3,799,679 to Simko is disclosed as an iris (38) is present near a detector which can be adjusted to block entry of backside reflection thereinto.

Patents to Meeks, Nos. 6,130,749, 6,198,533 and 6,392,749 are disclosed for the presence of a hole 2022 in an integrating sphere near, but not atop a sample.

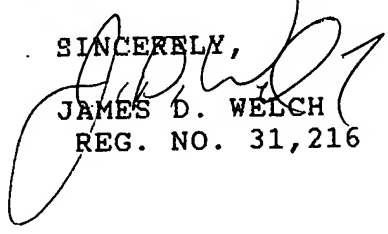
Patent No. 6,088,092 to Chen et al. is disclosed as it applies a spatial filter (28) to block backside reflection entry into a detector.

Patent No. 6,088,104 to Peterson is disclosed as a blocking element (B) is present which can be used to block electromagnetic radiation entry to a detector.

Patent No. 6,097,482 to Smith et al. is disclosed as it applies baffles to block light entry to a detector.

Patent No. 6,166,808 to Greve is disclosed as it describes use of an aperture near a detector to block backside reflections entry to a detector.

SINCERELY,

  
JAMES D. WELCH  
REG. NO. 31,216

Form PTO-1449  
REV. 7-04U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

SERIAL NO.

## LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Liphardt et al.

FILING DATE

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA		3799679	3/1974	Sinko	356	200	
AB		6130749	10/2000	Meeks et al.	356	381	
AC		6198533	3/2001	Meeks et al.	356	381	
AD		6392749	5/2002	Meeks et al.	356	387	
AE		6088092	7/2000	Chen et al.	356	237.2	
AF		6088104	7/2000	Peterson	356	371	
AG		6097482	8/2000	Smith et al.	356	237.1	
AH		6166808	12/2000	Greve	356	375	
AI							
AJ							
AK							

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
AL								
AM								

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AR		US 2002/0113200 A1, Published Application of Hajjar et al. 8/22/02						
AS								

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.